

Combinatorial Testing: Rationale and Impact

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What is NIST?

- US Government agency, whose mission is to support US industry through developing better measurement and test methods
- 3,000 scientists, engineers, and support staff including 4 Nobel laureates
- Research in physics, chemistry, materials, manufacturing, computer science
- Trivia: NIST is one of the only federal agencies chartered in the Constitution







Outline

- What is combinatorial testing?
- Why does it work?
- How does it work?
- Does it work in the real world?
- What are some research issues?

Where did these testing ideas come from?

Scottish physician James Lind determined cure of scurvy

Ship HM Bark Salisbury in 1747



12 sailors "were as similar as I could have them"

6 treatments 2 sailors for each – dilute sulfuric acid, seawater, vinegar, cider, orange/lemon juice, barley water

Principles used (blocking, replication, randomization)

Did not consider interactions, but otherwise used basic **Design of Experiments** principles



Father of DOE: R A Fisher, 1890-1962, British geneticist

Key features of Design of Experiments

- Blocking
- Replication
- Randomization
- Orthogonal arrays test interactions between two factors

- Each combination
- 2 occurs <u>same number</u>
 - of times, usually once.
 - Example: P1, P2 = 1,2



Four eras in evolution of DOE

- Era 1:(1920's ...): Beginning in agricultural then animal science, clinical trials, medicine
- Era 2:(1940's ...): Industrial productivity new field, same basics
- Era 3:(1980's ...): Designing robust products new field, same basics

Then things begin to change . . .

Era 4:(2000's ...): Combinatorial Testing of Software



Agriculture and biological investigations

System under investigation

Crop growing, effectiveness of drugs or other treatments Variable Types

Primary test factors (things farmer can adjust, drug dosages, etc.)

Relatively few, held constant

Numbers of treatments

Generally less than 10

Objectives: compare treatments to find better

Treatments: qualitative or discrete levels of continuous



Manufactured products

Scope of investigation:

Optimum levels of control factors at which variation from noise factors is minimum

Key principles

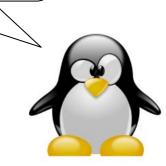
Variation from noise factors

Efficiency in testing; accommodate constraints

Designs: Based on Orthogonal arrays (OAs)

Taguchi designs (strength 2 orthogonal arrays)

Sounds great. Let's use it for software!



Orthogonal Arrays for Software Interaction Testing

Functional (black-box) testing

Hardware-software systems

Identify single and 2-way combination faults

Early papers

Taguchi followers (mid1980's) Mandl (1985) Compiler testing Tatsumi et al (1987) Fujitsu Sacks et al (1989) Computer experiments Brownlie et al (1992) AT&T

Generation of test suites using orthogonal arrays

OATS (Phadke, AT&T-BL)





What's different about software?

Traditional DoE

- Continuous variable results
- Few parameters
- Interactions typically increase or decrease output
- Statistical model requires balance

DoE for Software

- Binary result (pass or fail)
- Many parameters
- Interactions affect path through program
- Balance not needed

Does this difference make any difference?



So how did testing interactions work in practice for software?



- Pairwise, 2-factor, testing applied to software
- Intuition: some problems only occur as the result of an interaction between parameters/components
- Tests all pairs (2-way combinations) of variable values
- Pairwise testing finds about 50% to 90% of flaws

90% of flaws! Sounds pretty good!



Finding 90% of flaws is pretty good, right?



"Relax, our engineers found 90 percent of the flaws." I don't think I` want to get on that plane.



Maybe two factors are not enough?

- NIST studied software failures in 15 years of FDA medical device recall data
- What causes software failures?
 - logic errors? calculation errors?
- What testing would have detected errors?



Also found interaction faults: e.g., failure occurs if pressure < 10 && volume > 300 (2 factors)

Example from FDA failure analysis: Failure when "altitude adjustment set on 0 meters and total flow volume set at delivery rate of less than 2.2 liters per minute."

What does an interaction fault look like?

How does an interaction fault manifest itself in code? Example: altitude_adj == 0 && volume < 2.2 (2-way interaction)

- if (altitude_adj == 0) {
 - // do something
 - if (volume < 2.2) { faulty code! BOOM! }</pre>

else { good code, no problem}

} else {

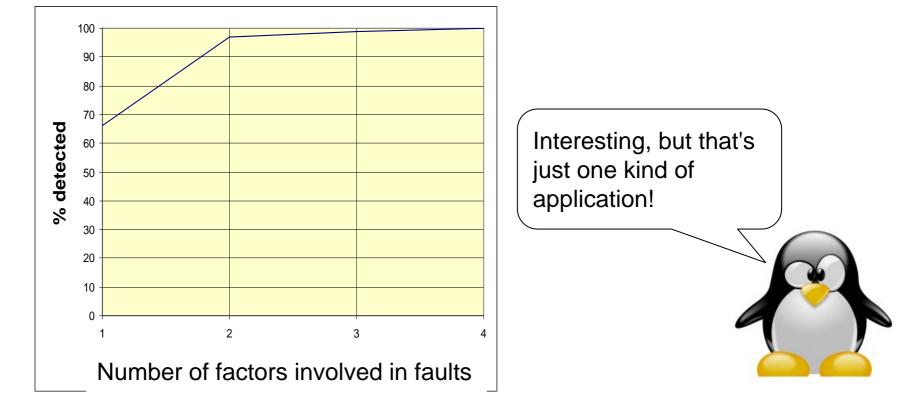
```
// do something else
```

}
A test with altitude_adj == 0 and volume = 1 would find this
Again, ~ 90% of the FDA failures were 2-way or 1-way

... but some involved more than 2 factors

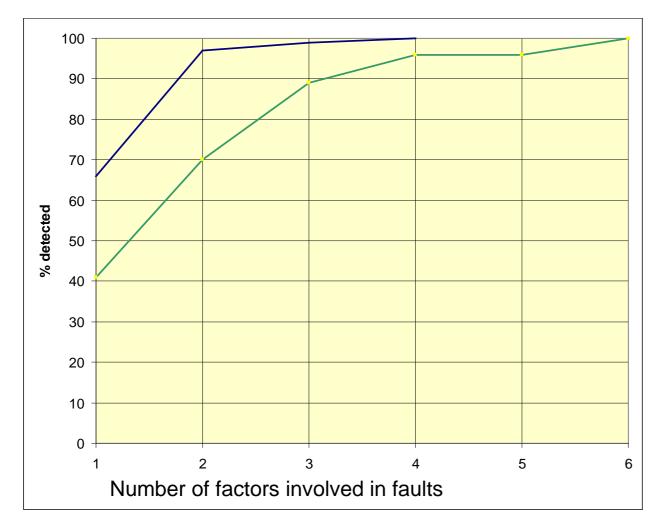
How are interaction faults distributed?

- Interactions e.g., failure occurs if pressure < 10 pressure < 10 & volume > 300 pressure < 10 & volume > 300 & velocity = 5
 (3-way interaction)
- Surprisingly, no one had looked at interactions beyond 2-way before
- The most complex medical device failure reported required 4-way interaction to trigger.



What about other applications?

Server (green)



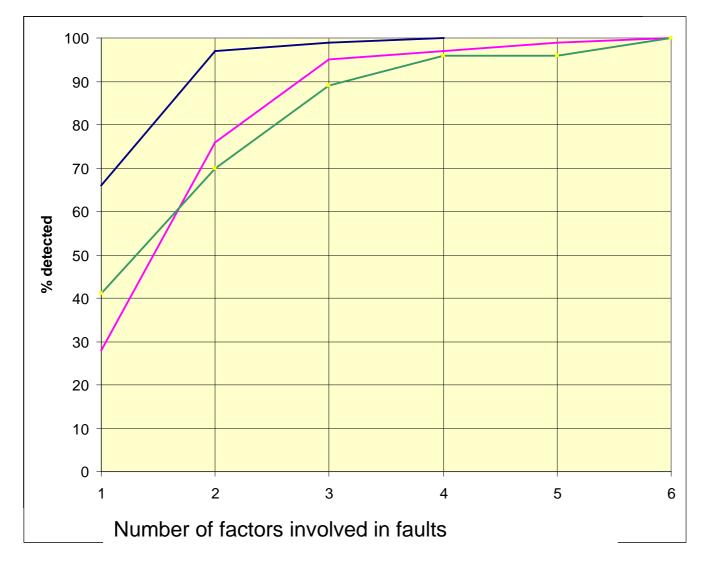
These faults more complex than medical device software!!

Why?





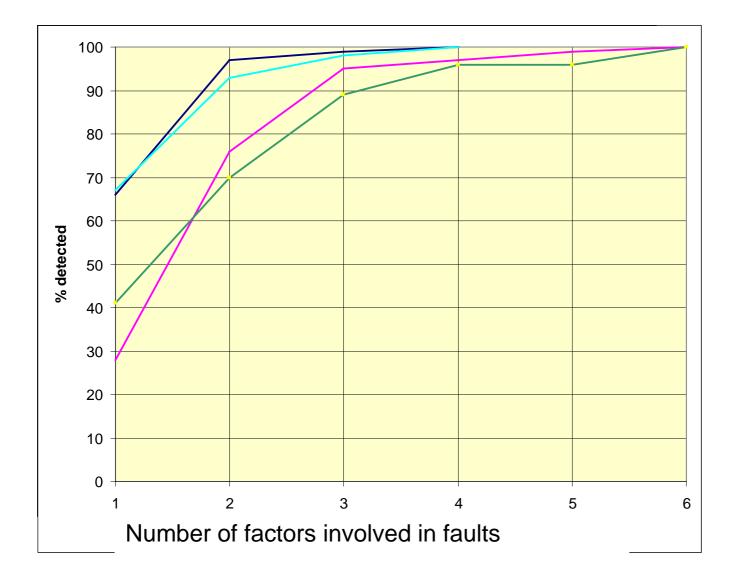
Browser (magenta)





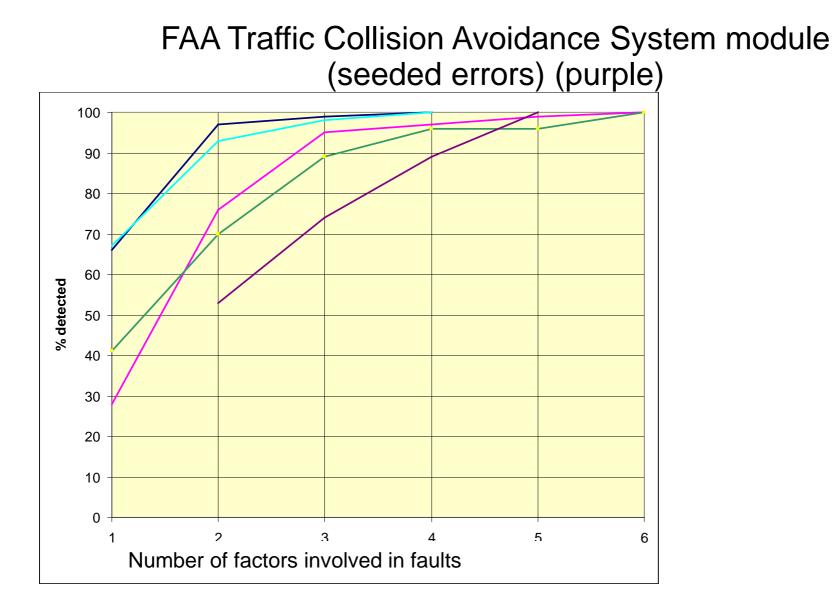
Still more?

NASA Goddard distributed database (light blue)





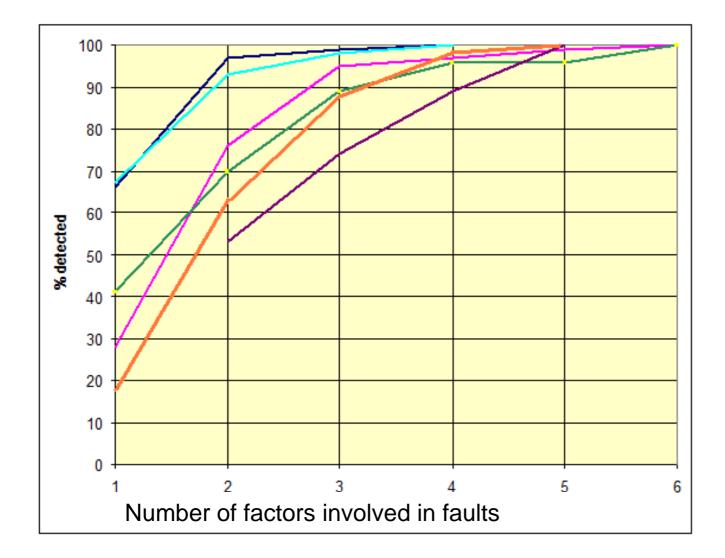
Even more?





Finally

Network security (Bell, 2006) (orange)

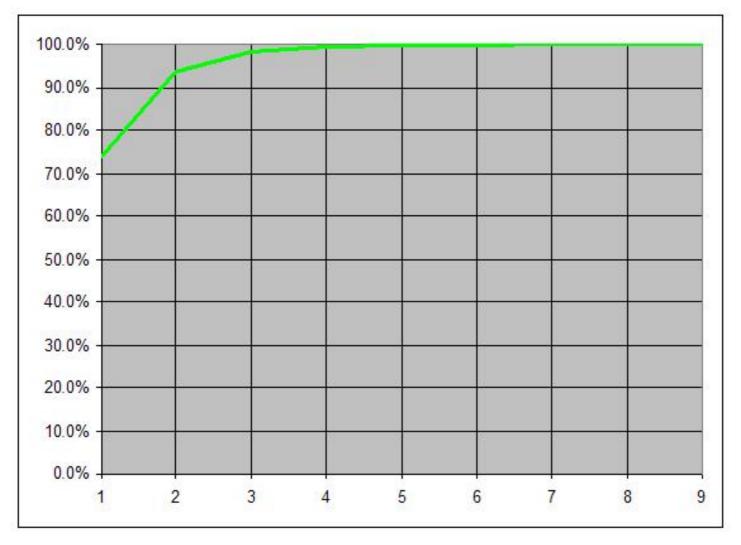


Curves appear to be similar across a variety of application domains.



What causes this distribution?

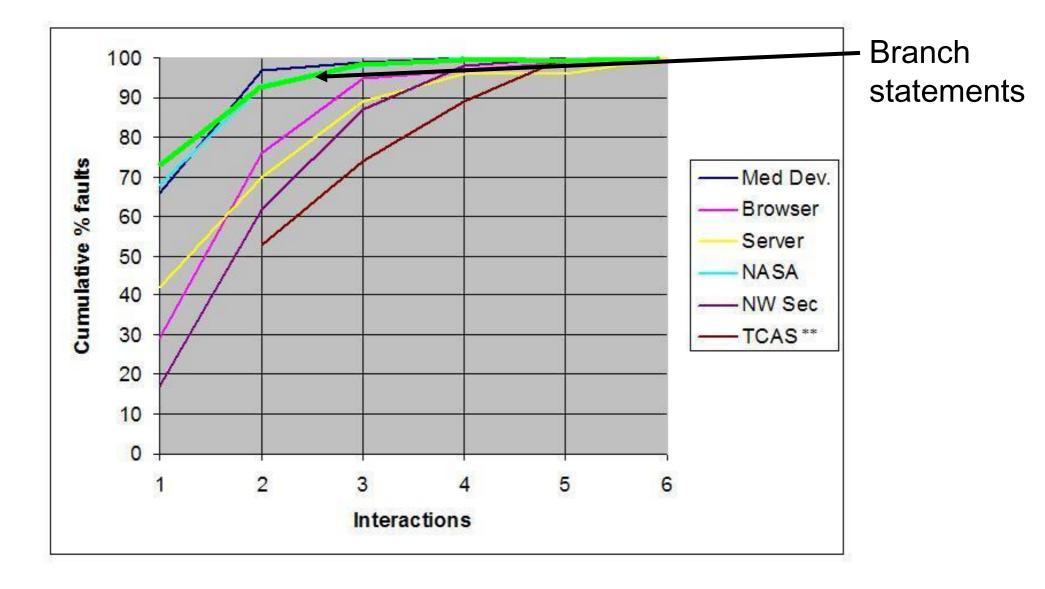




One clue: branches in avionics software. 7,685 expressions from *if* and *while* statements

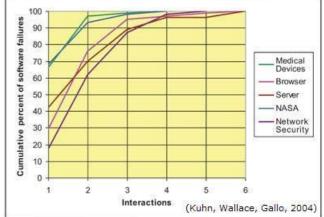
Comparing with Failure Data





Interaction Rule

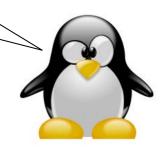
 Refers to how many parameters are involved in faults:



Interaction rule: most failures are triggered by one or two parameters, and progressively fewer by three, four, or more parameters, and the maximum interaction degree is small.

- Maximum interactions for fault triggering was <u>6</u>
- Two-factor testing <u>not enough</u>
- Reasonable evidence that maximum interaction strength for fault triggering is relatively small

How does it help me to know this?



How does this knowledge help?

If all faults are triggered by the interaction of *t* or fewer variables, then testing all *t*-way combinations can provide strong assurance.

- New algorithms make it <u>practical</u> to test these combinations
- (however: value propagation issues, equivalence partitioning, timing issues, more complex interactions,...)

Still no silver bullet. Rats!

Let's see how to use this knowledge in testing. A simple example:

Font				?
Fo <u>n</u> t	Character Spacing	Te <u>x</u> t Effects		
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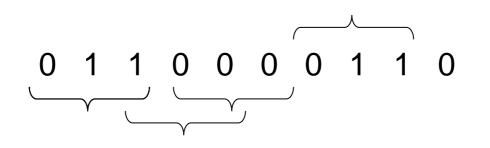
How Many Tests Would It Take?

- There are 10 effects, each can be on or off
- All combinations is 2¹⁰ = 1,024 tests
- What if our budget is too limited for these tests?
- Instead, let's look at all 3-way interactions

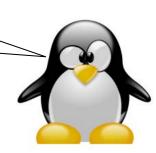


Now How Many Would It Take?

- There are $\begin{bmatrix} 10\\ 3 \end{bmatrix} = 120$ 3-way interactions.
- Naively 120 x 2³ = 960 tests.
- Since we can pack 3 triples into each test, we need no more than 320 tests.
- Each test exercises many triples:



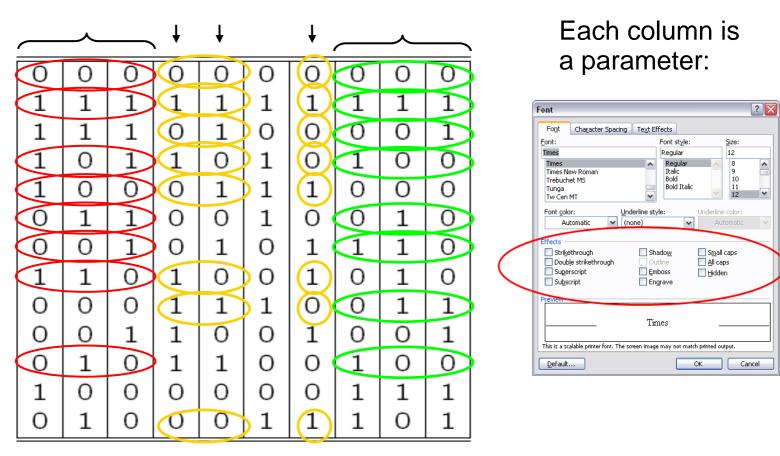
OK, OK, what's the smallest number of tests we need?



A covering array

All triples in only 13 tests, covering $\begin{bmatrix} 10\\ 3 \end{bmatrix} 2^3 = 960$ combinations

Each row is a test:



- Developed 1990s
- Extends Design of Experiments concept
- Difficult mathematically but good algorithms now



Design of Experiments for Software Testing

Not orthogonal arrays, but <u>Covering arrays</u>: Fixed-value CA(*N*, *v^k*, *t*) has four parameters *N*, *k*, *v*, *t* : It is a matrix covers every t-way combination <u>at least once</u>

Early developments by Tatsumi, Sherwood

Key differences

orthogonal arrays:

- Combinations occur <u>same number of times</u>
- <u>Only exist</u> for a certain configurations

covering arrays:

- Combinations occur
 <u>at least once</u>
- <u>Always possible to find for</u> any configuration
- <u>Always smaller</u> than orthogonal array (or same)

A larger example

Suppose we have a system with 34 on-off switches. Software must produce the right response for any combination of switch settings:





How do we test this?

34 switches = 2^{34} = 1.7 x 10¹⁰ possible inputs = 1.7 x 10¹⁰ tests





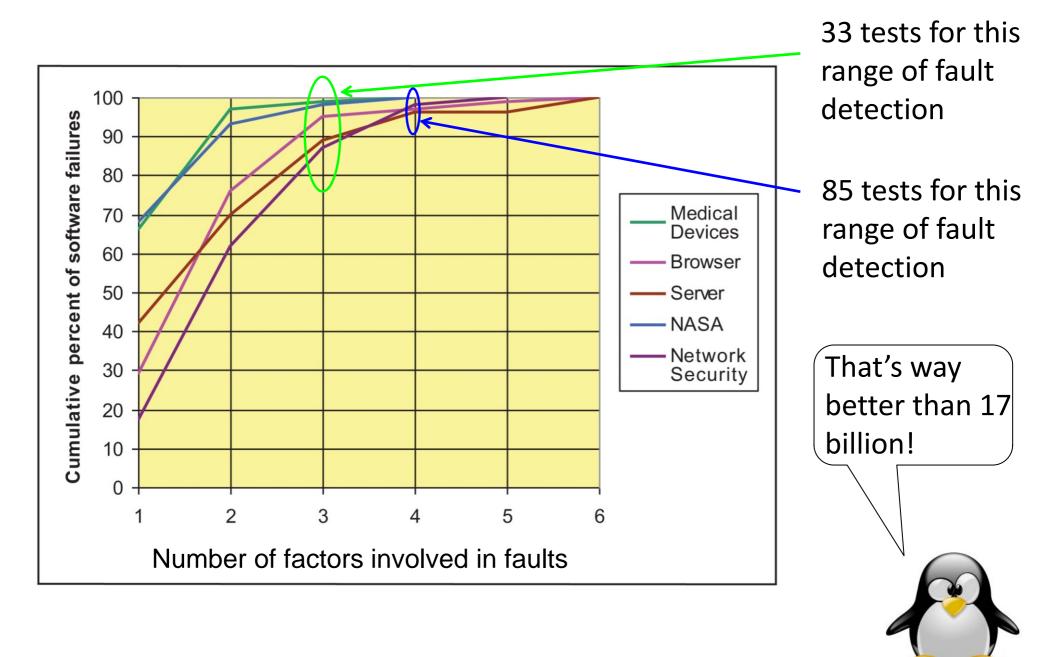
What if we knew no failure involves more than 3 switch settings interacting?

- 34 switches = 2^{34} = 1.7 x 10¹⁰ possible inputs = **1.7 x 10¹⁰** tests
- If only 3-way interactions, need only 33 tests
- For 4-way interactions, need only 85 tests

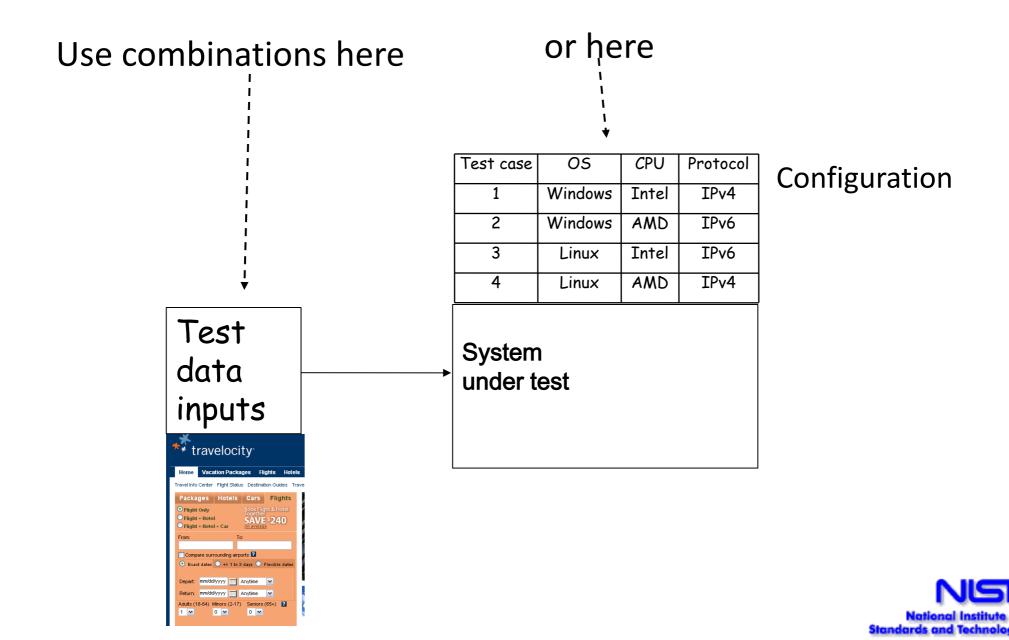




Do we have enough tests?



We can also use it on configurations



Testing Configurations

- Example: app must run on any configuration of OS, browser, protocol, CPU, and DBMS
- Very effective for interoperability testing,

Test	OS	Browser	Protocol	CPU	DBMS
1	XP	IE	IPv4	Intel	MySQL
2	XP	Firefox	IPv6	AMD	Sybase
3	XP	IE	IPv6	Intel	Oracle
4	OS X	Firefox	IPv4	AMD	MySQL
5	OS X	IE	IPv4	Intel	Sybase
6	OS X	Firefox	IPv4	Intel	Oracle
7	RHL	IE	IPv6	AMD	MySQL
8	RHL	Firefox	IPv4	Intel	Sybase
9	RHL	Firefox	IPv4	AMD	Oracle
10	OS X	Firefox	IPv6	AMD	Oracle

- But something is wrong here ... there is no Linux & IE configuration
- Covering array tools can avoid such invalid combinations

Testing Smartphone Configurations

Some Android configuration options:

int HARDKEYBOARDHIDDEN NO; int HARDKEYBOARDHIDDEN_UNDEFINED; int HARDKEYBOARDHIDDEN YES; int KEYBOARDHIDDEN NO; int KEYBOARDHIDDEN UNDEFINED; int KEYBOARDHIDDEN YES; int KEYBOARD 12KEY; int KEYBOARD NOKEYS; int KEYBOARD QWERTY; int KEYBOARD UNDEFINED; int NAVIGATIONHIDDEN NO; int NAVIGATIONHIDDEN UNDEFINED; int NAVIGATIONHIDDEN YES; int NAVIGATION DPAD; int NAVIGATION_NONAV; int NAVIGATION TRACKBALL; int NAVIGATION UNDEFINED; int NAVIGATION_WHEEL;

int ORIENTATION LANDSCAPE; int ORIENTATION PORTRAIT; int ORIENTATION SQUARE; int ORIENTATION UNDEFINED; int SCREENLAYOUT_LONG_MASK; int SCREENLAYOUT_LONG_NO; int SCREENLAYOUT LONG UNDEFINED; int SCREENLAYOUT LONG YES; int SCREENLAYOUT_SIZE_LARGE; int SCREENLAYOUT SIZE MASK; int SCREENLAYOUT_SIZE_NORMAL; int SCREENLAYOUT SIZE SMALL; int SCREENLAYOUT SIZE UNDEFINED; int TOUCHSCREEN FINGER; int TOUCHSCREEN NOTOUCH; int TOUCHSCREEN STYLUS; int TOUCHSCREEN_UNDEFINED;



Configuration option values

Parameter Name	Values	# Values
HARDKEYBOARDHIDDEN	NO, UNDEFINED, YES	3
KEYBOARDHIDDEN	NO, UNDEFINED, YES	3
KEYBOARD	12KEY, NOKEYS, QWERTY, UNDEFINED	4
NAVIGATIONHIDDEN	NO, UNDEFINED, YES	3
NAVIGATION	DPAD, NONAV, TRACKBALL, UNDEFINED, WHEEL	5
ORIENTATION	LANDSCAPE, PORTRAIT, SQUARE, UNDEFINED	4
SCREENLAYOUT_LONG	MASK, NO, UNDEFINED, YES	4
SCREENLAYOUT_SIZE	LARGE, MASK, NORMAL, SMALL, UNDEFINED	5
TOUCHSCREEN	FINGER, NOTOUCH, STYLUS, UNDEFINED	4

Total possible configurations:

3 x 3 x 4 x 3 x 5 x 4 x 4 x 5 x 4 = 172,800



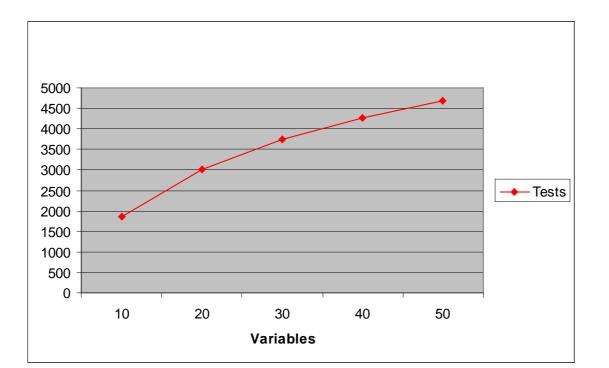
Number of configurations generated for *t*-way interaction testing, t = 2..6

t	# Configs	% of Exhaustive
2	29	0.02
3	137	0.08
4	625	0.4
5	2532	1.5
6	9168	5.3



How many tests are needed?

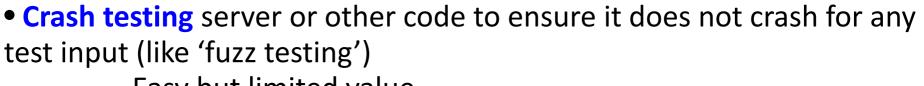
- Number of tests: proportional to v^t log n for v values, n variables, t-way interactions
- Thus:
 - Tests increase *exponentially* with interaction strength *t*
 - But *logarithmically* with the number of parameters
- Example: suppose we want all 4-way combinations of *n* parameters, 5 values each:



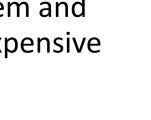


How do we automate checking correctness of output?

- Creating test data is the easy part!
- How do we check that the code worked correctly on the test input?



- Easy but limited value
- Built-in self test with embedded assertions incorporate assertions in code to check critical states at different points in the code, or print out important values during execution
- Full scale model-checking using mathematical model of system and model checker to generate expected results for each input - expensive but tractable



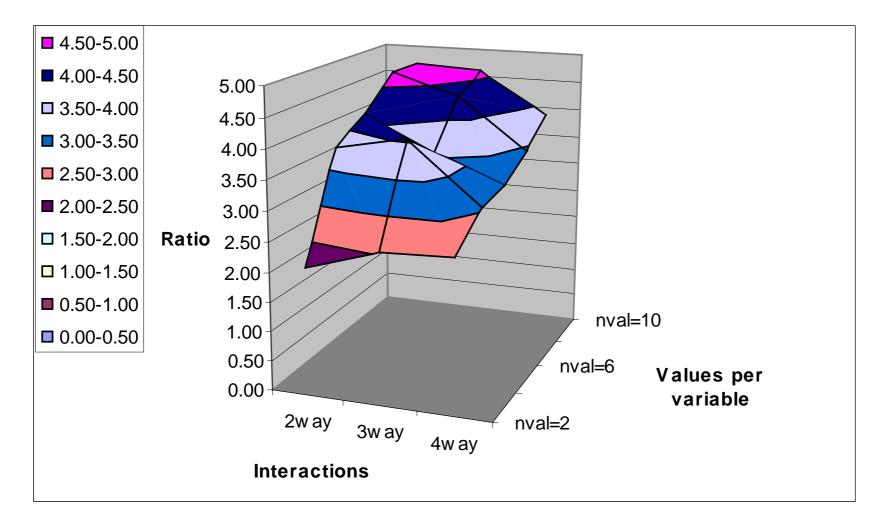


Crash Testing

- Like "fuzz testing" send packets or other input to application, watch for crashes
- Unlike fuzz testing, input is non-random; cover all t-way combinations
- May be more efficient random input generation requires several times as many tests to cover the t-way combinations in a covering array
 - Limited utility, but can detect high-risk problems such as:
 - buffer overflows
 - server crashes



Ratio of Random/Combinatorial Test Set Required to Provide t-way Coverage





Embedded Assertions

Assertions check properties of expected result:

ensures balance == \old(balance) - amount
&& \result == balance;

•Reasonable assurance that code works correctly across the range of expected inputs

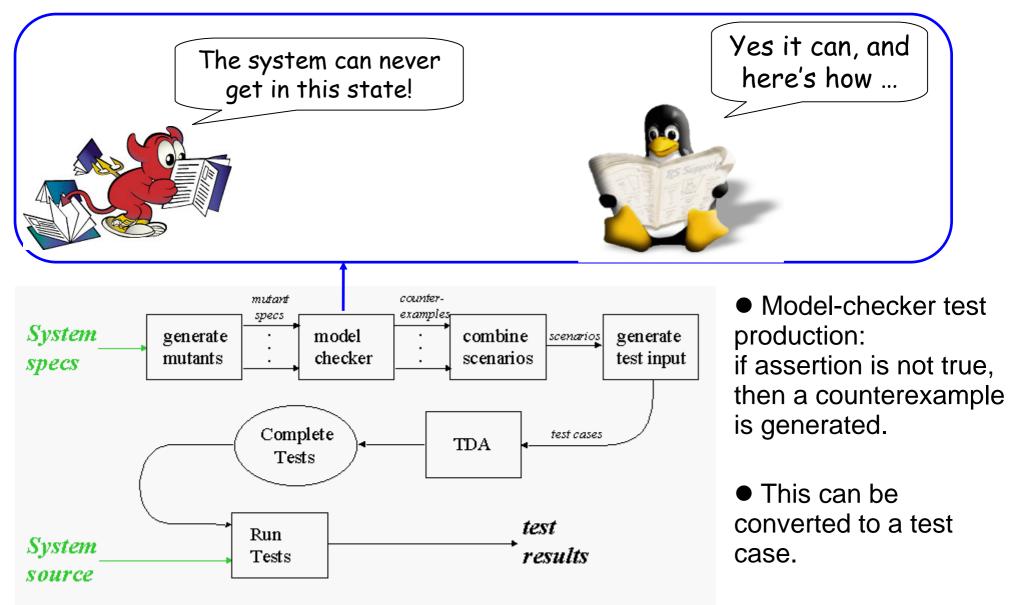
•May identify problems with handling unanticipated inputs

- •Example: Smart card testing
 - Used Java Modeling Language (JML) assertions
 - Detected 80% to 90% of flaws





Using model checking to produce tests



Black & Ammann, 1999

Testing inputs

Traffic Collision Avoidance
 System (TCAS) module



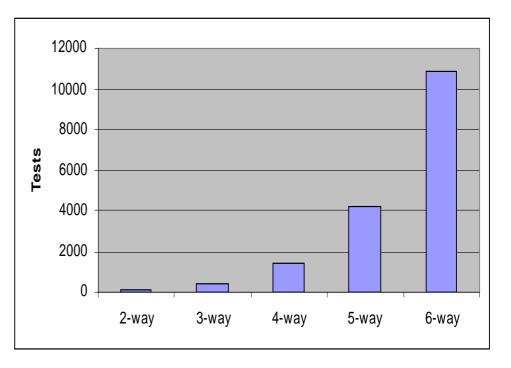
- Used in previous testing research
- 41 versions seeded with errors
- 12 variables: 7 boolean, two 3-value, one 4value, two 10-value
- All flaws found with 5-way coverage
- Thousands of tests generated by model checker in a few minutes





Tests generated

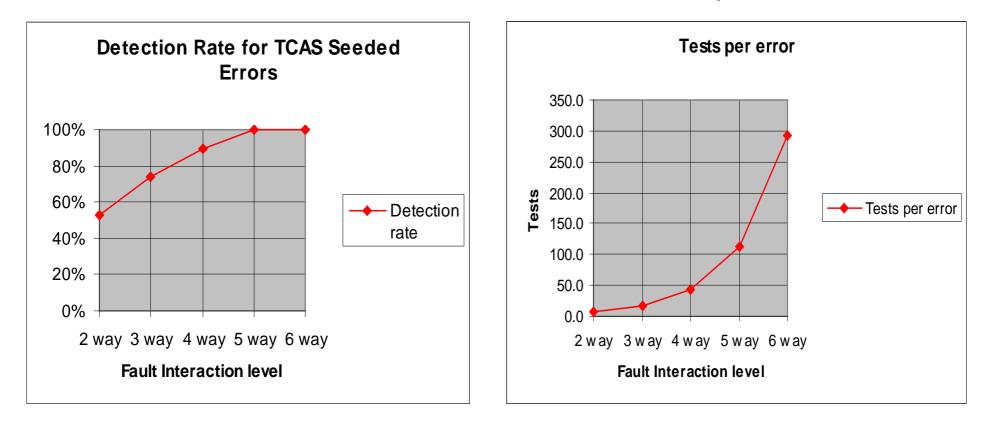
t	Test cases		
2-way:	156		
3-way:	461		
4-way:	1,450		
5-way:	4,309		
6-way:	11,094		







- Roughly consistent with data on large systems
- But errors harder to detect than real-world examples



Bottom line for model checking based combinatorial testing: Requires more technical skill but can be highly effective

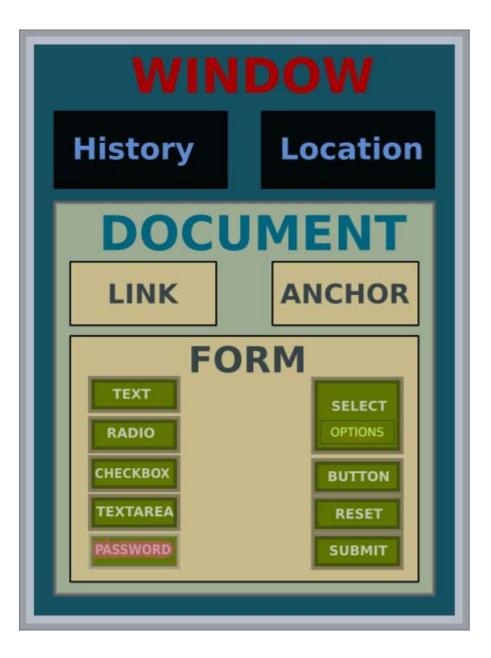


What good is combinatorial testing?

- 2.5 year Lockheed Martin study, 8 pilot projects in aerospace software
- Results: "Lockheed Martin's initial estimate is that this method supported by the technology can save up to 20% of test planning/design costs if done early on a program while increasing test coverage by 20% to 50%."



Example 1: Document Object Model Events



- DOM is a World Wide Web Consortium standard for representing and interacting with browser objects
- NIST developed conformance tests for DOM
- Tests covered all possible combinations of discretized values, >36,000 tests
- Question: can we use the Interaction Rule to increase test effectiveness the way we claim?



Document Object Model Events Original test set:

Event Name	Param.	Tests
Abort	3	12
Blur	5	24
Click	15	4352
Change	3	12
dblClick	15	4352
DOMActivate	5	24
DOMAttrModified	8	16
DOMCharacterDataMo dified	8	64
DOMElementNameCha nged	6	8
DOMFocusIn	5	24
DOMFocusOut	5	24
DOMNodeInserted	8	128
DOMNodeInsertedIntoD ocument	8	128
DOMNodeRemoved	8	128
DOMNodeRemovedFrom Document	ı 8	128
DOMSubTreeModified	8	64
Error	3	12
Focus	5	24
KeyDown	1	17
KeyUp	1	17

Load	3	24
MouseDown	15	4352
MouseMove	15	4352
MouseOut	15	4352
MouseOver	15	4352
MouseUp	15	4352
MouseWheel	14	1024
Reset	3	12
Resize	5	48
Scroll	5	48
Select	3	12
Submit	3	12
TextInput	5	8
Unload	3	24
Wheel	15	4096
Total Tests		36626

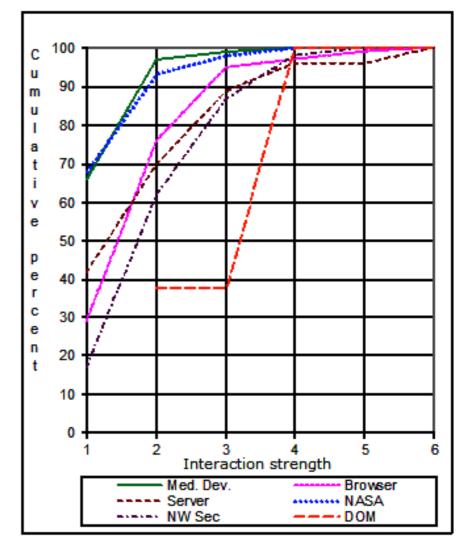
Exhaustive testing of equivalence class values



Document Object Model Events Combinatorial test set:

		% of Orig.	-	lest Resu	lts
t	Tests		Pass	Fail	Not Run
2	702	1.92%	202	27	473
3	1342	3.67%	786	27	529
4	1818	4.96%	437	72	1309
5	2742	7.49%	908	172	1762
6	4227	11.54 %	1803	72	2352
			\setminus /		

All failures found using < 5% of original exhaustive test set





Example 2: Laptop application testing



Connection Sequences

		,	P-2 (USB-	P-3 (USB-				
1	Boot	RIGHT)	BACK)	LEFT)	P-4	P-5	App	Scan
						P-3 (USB-	P-2 (USB-	P-1 (USB-
2	Boot	App	Scan	P-5	P-4	RIGHT)	BACK)	LEFT)
		P-3 (USB-	P-2 (USB-	P-1 (USB-				
3	Boot	RIGHT)	LEFT)	BACK)	App	Scan	P-5	P-4
	etc							

Event Sequence Testing

- Suppose we want to see if a system works correctly regardless of the order of events. How can this be done efficiently?
- Failure reports often say something like: 'failure occurred when A started if B is not already connected'.
- Can we produce compact tests such that all t-way sequences covered (possibly with interleaving events)?

Event	Description
а	connect video
b	connect range finder
С	connect satellite link
d	connect navigation
е	start comm link
f	boot system



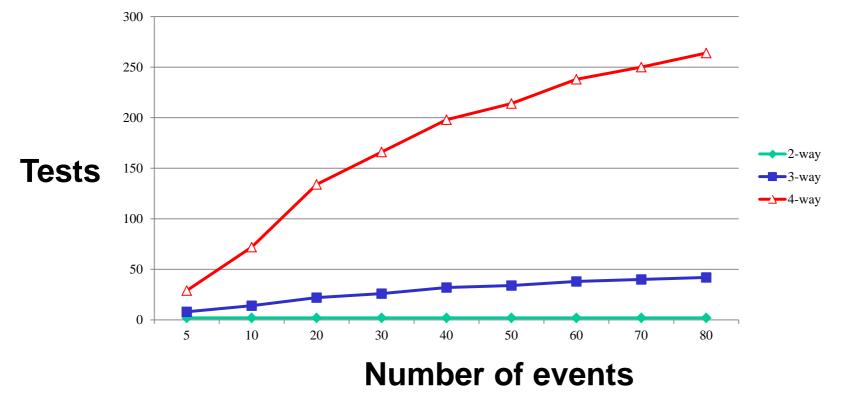
Sequence Covering Array

- With 6 events, all sequences = 6! = 720 tests
- Only 10 tests needed for all 3-way sequences, results even better for larger numbers of events
- Example: .*c.*f.*b.* covered. Any such 3-way seq covered.

	Test	Sequence					
	1	а	b	С	d	е	f
/	2	f	е	d	С	b	а
	3	d	е	f	а	b	С
	4	С	b	а	f	е	d
	5	b	f	а	d	С	е
X	6	е	С	d	а	f	b
	7	а	е	f	С	b	d
	8	d	b	С	f	е	а
	9	С	е	а	d	b	f
	10	f	b	d	а	е	С

Sequence Covering Array Properties

- 2-way sequences require only 2 tests (write events in any order, then reverse)
- For > 2-way, number of tests grows with log *n*, for *n* events
- Simple greedy algorithm produces compact test set
- Not previously described in CS literature (but pure math paper 1970s!)





Example 3: Existing Test Sets

- Will this method disrupt my test process?
- What if I already have a large set of tests? Does this approach add anything?
- NASA spacecraft software test set, approx 7,500 tests
- Does it already provide 2-way, 3-way, 4-way coverage?

Measuring Combinatorial Coverage

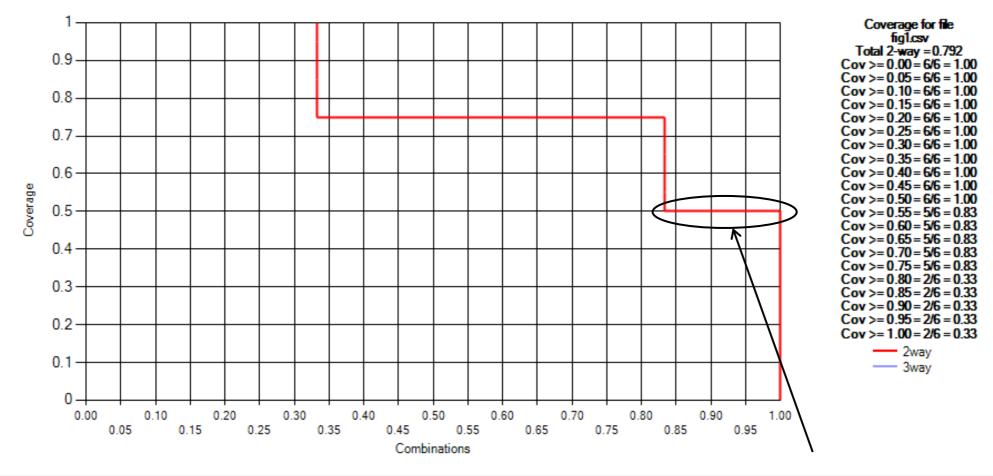
Tests	Variables			
	а	b	С	d
1	0	0	0	0
2	0	1	1	0
3	1	0	0	1
4	0	1	1	1

Variable pairs	Variable-value combinations covered	Coverage
ab	00, 01, 10	.75
ас	00, 01, 10	.75
ad	00, 01, 11	.75
bc	00, 11	.50
bd	00, 01, 10, 11	1.0
cd	00, 01, 10, 11	1.0

100% coverage of 33% of combinations75% coverage of half of combinations50% coverage of 16% of combinations



Graphing Coverage Measurement

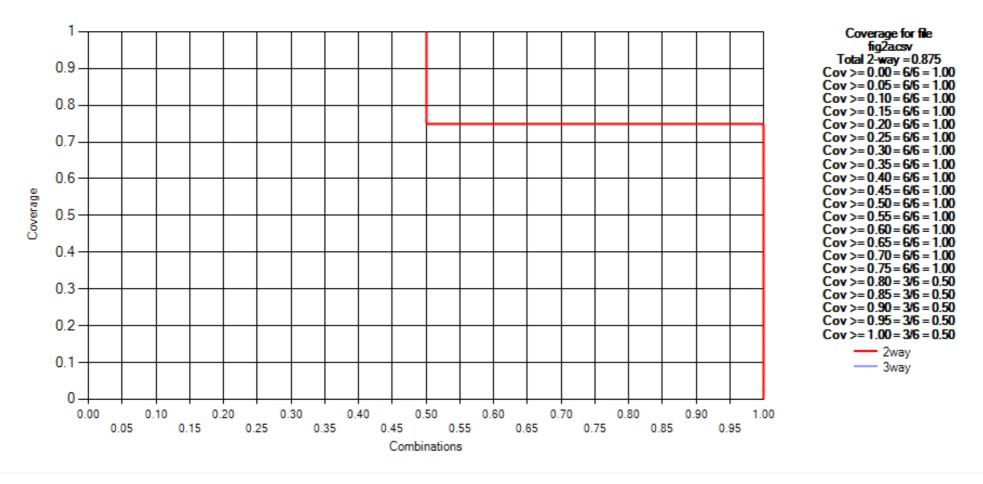


100% coverage of 33% of combinations75% coverage of half of combinations50% coverage of 16% of combinations

Bottom line: All combinations covered to at least 50%



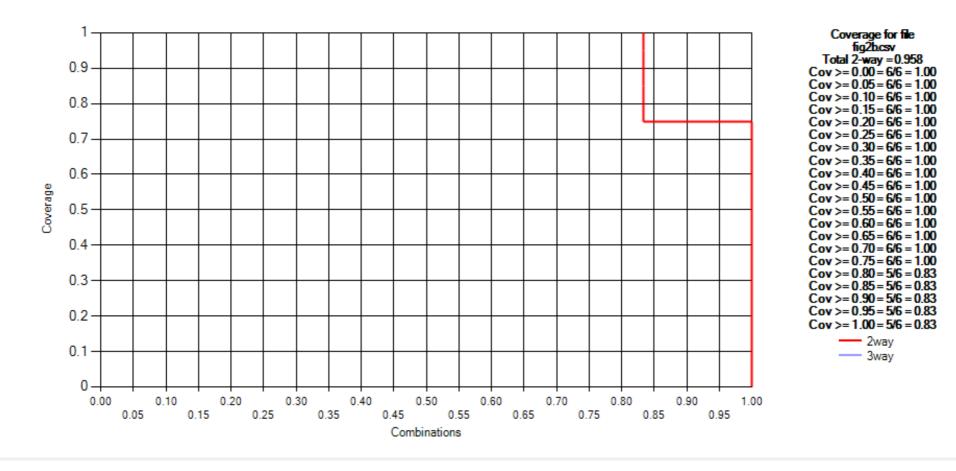
Adding a test



Coverage after adding test [1,1,0,1]



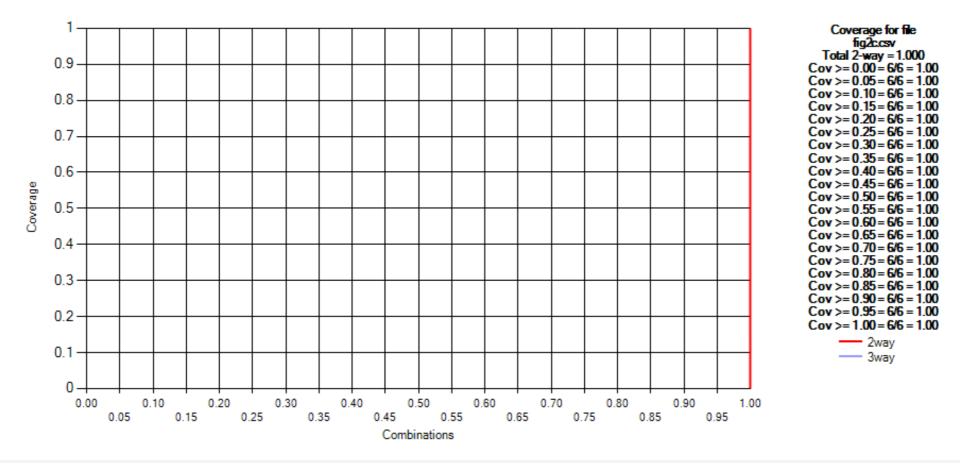
Adding another test



Coverage after adding test [1,0,1,1]



Additional test completes coverage



Coverage after adding test [1,0,1,0] All combinations covered to 100% level, so this is a covering array.

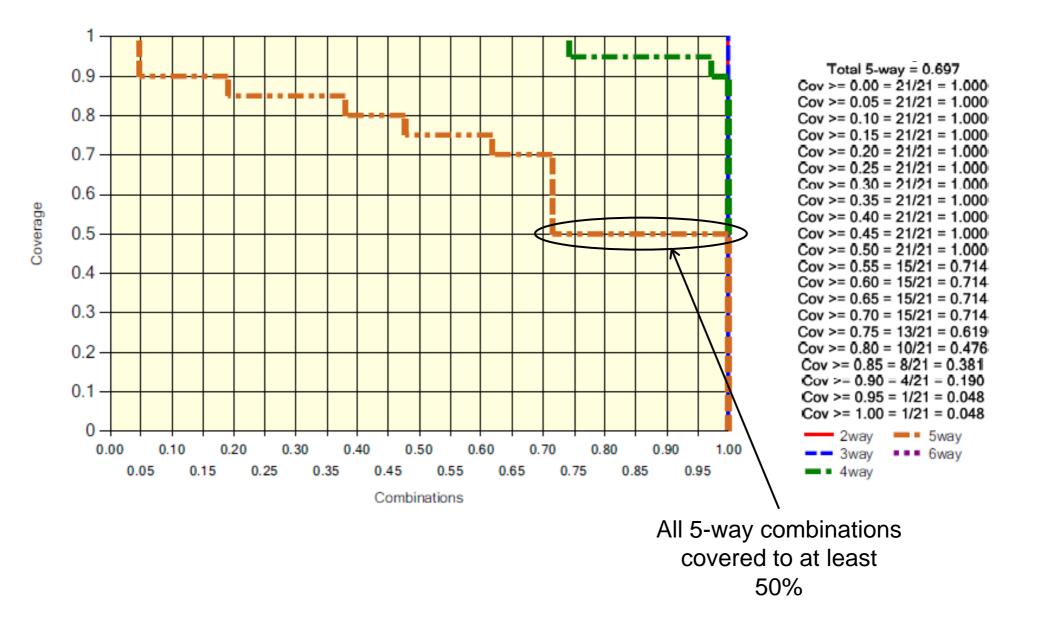


Combinatorial Coverage Measurement

Auto-detect N tests, N parms	Combinatorial Coverage Measurement
Number of tests 7489 Number of parameters 82 Set number of tests and parameters Load input file Show input file 7489 tests, 82 parameters loaded	● Detect all values automatically ● Set boundaries for equivalence classes Parameter 0 Detect Prev Next N classes 2 The set of the se
Compute 2-way coverage Compute 3-way coverage Clear chart Save chart Exit Chart X = proportion of combinations Y = combination variable-value coverage	1 Coverage for file 0.9 0.8 0.8 0.8 0.8 0.9 0.8 0.0 0.8 0.0 <
2 way stats: Combinations: 3,321 Var/val coms: 14,761 Total coverage: 0.940 3 way stats: Combinations: 88,560 Var/val coms: 828,135	$\begin{array}{c c c c c c c c c c c c c c c c c c c $
Total coverage: 0.831	0.05 0.15 0.25 0.35 0.45 0.55 0.65 0.75 0.85 0.95 Combinations



USAF test plan coverage



Where do we go next?

- "Internet of things" testing problem enormous
 - Vast number of interacting components
 - Combinatorial testing is a natural fit
- Cyber-physical systems
 - Safety aspects
 - Another natural fit with combinatorial methods
- Test development environment
 - Define the data model critical for testing
 - Classification tree tool project at CMU
- Many research questions



Algorithms

- Highly effective now, but room for improvements
- Algebraic
 - Very compact arrays, but some configurations can't be computed, problems with constraints
- Computational (greedy, simulated annealing, hill climbing, genetic)
 - May produce more tests, but always possible, good constraint handling
- Post optimization and array reduction advances announced at this conference! (CAS, Nanjing)
- Current best known sizes:

http://www.public.asu.edu/~ccolbou/src/tabby/catable.html



Test Prioritization

Given a set of tests, what permutation finds faults fastest?

Tests can be ordered by various criteria:

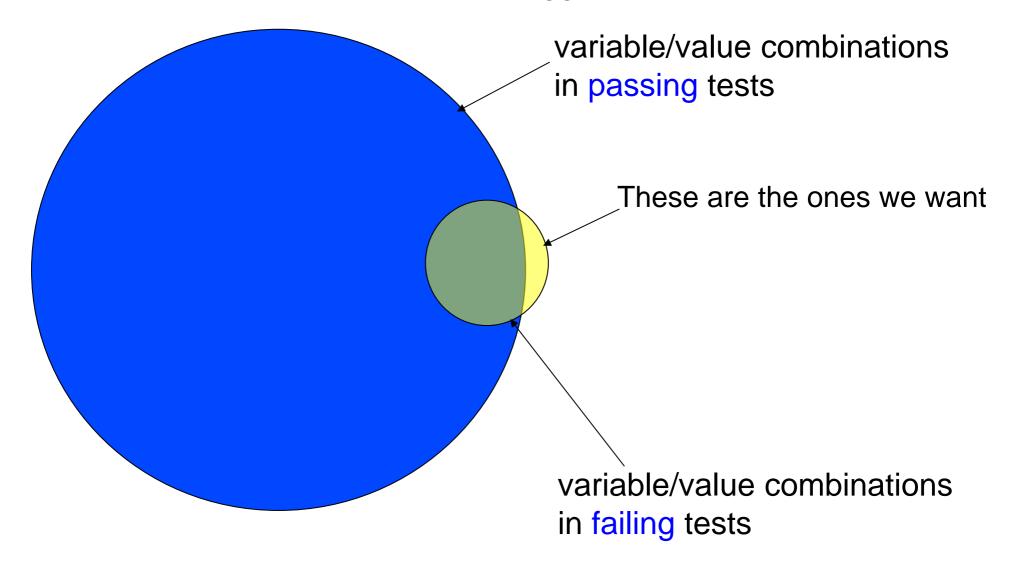
- Combination coverage (equiv to greedy algo)
- Hamming distance
- Random
- Application-specific criterion

Especially important for GUI testing

Fault location



Given: a set of tests that the SUT fails, which combinations of variables/values triggered the failure?



Fault location – what's the problem?

If they're in failing set but not in passing set:

1. which ones triggered the failure?

2. which ones don't matter?

out of $v^t \binom{n}{t}$ combinations

Example:

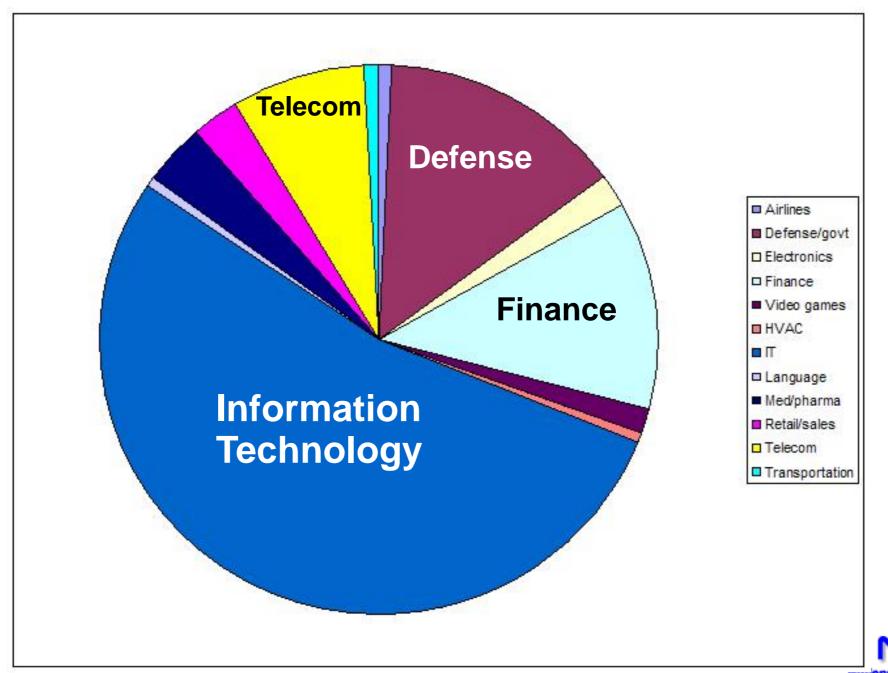
- 30 variables, 5 values each
- = 445,331,250

5-way combinations

142,506 combinations in each test



Users and Tech Transfer



Standards and Technology

Lessons Learned and Needs

- Education and training materials tutorial, textbook
- Greater availability of tools to support combinatorial testing see pairwise.org
- Modify approaches to using combinatorial testing integrating combinatorial testing with other test practices; ability to adopt CT partially or gradually – measurement tool
- Incorporate combinatorial methods into DoD guidance and industry standards; develop a community of practice

Review video by Tyler Mesch, Bose Corp.

Thank you for listening!





BACKUP SLIDES FOR ADDITIONAL DISCUSSION

Examples from the National Vulnerability Database

Single variable, 1-way interaction example: Heap-based buffer overflow in the SFTP protocol handler for Panic Transmit ... allows remote attackers to execute arbitrary code via a long ftps:// URL.

2-way interaction

example: **single character search string** in conjunction with a **single character replacement string**, which causes an "off by one overflow"

3-way interaction

example: Directory traversal vulnerability when register_globals is enabled and magic_quotes is disabled and .. (dot dot) in the page parameter

Example 2: Problem: unknown factors causing failures of F-16 ventral fin



Figure 1. LANTIRN pod carriage on the F-16.

It's not supposed to look like this:



Figure 2. F-16 ventral fin damage on flight with LANTIRN

Can the problem factors be found efficiently?

Original solution: Lockheed Martin engineers spent many months with wind tunnel tests and expert analysis to consider interactions that could cause the problem

Combinatorial testing solution: modeling and simulation using ACTS

Parameter	Values
Aircraft	15, 40
Altitude	5k, 10k, 15k, 20k, 30k, 40k, 50k
	hi-speed throttle, slow accel/dwell, L/R 5 deg
	side slip, L/R 360 roll, R/L 5 deg side slip, Med
	accel/dwell, R-L-R-L banking, Hi-speed to Low,
Maneuver	360 nose roll
Mach (100 th)	40, 50, 60, 70, 80, 90, 100, 110, 120

Results

- Interactions causing problem included Mach points .95 and .97; multiple side-slip and rolling maneuvers
- Solution analysis tested interactions of Mach points, maneuvers, and multiple fin designs
- Problem could have been found much more efficiently and quickly
- Less expert time required
- Spreading use of combinatorial testing in the corporation:
 - Community of practice of 200 engineers
 - Tutorials and guidebooks
 - Internal web site and information forum

What tools are available?

- **Covering array generator** basic tool for test input or configurations;
- Sequence covering array generator new concept; applies combinatorial methods to event sequence testing
- Combinatorial coverage measurement detailed analysis of combination coverage; automated generation of supplemental tests; helpful for integrating c/t with existing test methods
- Domain/application specific tools:
 - Access control policy tester
 - .NET config file generator



ACTS - Defining a new system

🕌 New System Form

		Saved Parameters	
System Name	TCAS	Paramater Name	Parameter Value
System indine	Teno	Cur_Vertical_Sep	[299,300,601]
		High_Confidence	[true,false]
ystem Parameter —		Two_of_Three_Reports	[true,false]
		Own_Tracked_Alt	[1,2]
Parameter Name		Other_Track_Alt	[1,2]
		Own_Tracked_Alt_Rate	[600,601]
Parameter Type	Boolean 💌	Alt_Layer_Value	[0,1,2,3]
		Up_Separation	[0,399,400,499,500,639,640,7
		Down_Separation	[0,399,400,499,500,639,640,7
arameter Values —		Other_RAC	[NO_INTENT,DO_NOT_CLIMB,
Selected Parameter	Boolean	Other_Capability	[TCAS_CA,Other]
		Climb_Inhibit	[true,false]
Range Value Add-> Remove->	true,false	3	
			Remove Modify



×

Variable interaction strength



Constraints

Modify System	
Parameters Relatores Constraints	
Palette P V [()] = != > < <= >= 66 => ! * / - % +	Added Constraints Constraints
Contrast Editor	
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Plod fy System	[[



Covering array output

m Edit Operations Help	Service Services		and the second			a second	e a na a sera						
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System View	Te:	st Result	Stati:	stics									
[Root Node] [SYSTEM-TCAS]		CUR_V	HIGH	TWO	OWN	OTHER	OWN	ALT_L	UP_SE	DOWN	OTHE	OTHER	CLIM
English Cur_Vertical_Sep	1	299	true	true	1	1	600	0	0	0	NO_INT T	CAS_TA	true
• 299	2	300	false	false	2	2	601	1	0	399	DO_NO 0	DTHER	false
• 300	3	601	true	false	1	2	600	2	0	400	DO_NO C	DTHER	true
• 601	4	299	false	true	2	1	601	3	0	499	DO_NO T	ICAS_TA	false
High_Confidence	5	300	false	true	1	1	601	0	0	500	DO_NO C	DTHER	true
true	6	601	false	true	2	2	600	1	0	639	NO_INT T	CAS_TA	false
• false	7	299	false	false	2	1	601	2	0	640	NO_INT T	CAS_TA	true
Two of Three Reports	8	300	true	false	1	2	600	3	0	739	NO_INT C	DTHER	false
true	9	601	true	false	2	1	601	0	0	740	DO_NO T	CAS_TA	true
 false 	10	299	true	true	1	2	600	1	0	840	DO_NO 0	DTHER	false
Own_Tracked_Alt	11	300	false	true	1	2	600	2	399	0	DO_NO T	CAS_TA	false
	12	601	true	false	2	1	601	3	399	399	DO_NO T	CAS_TA	true
• 1 • 2	13	299	false	true	2	1	601	0	399	400	NO_INT C	DTHER	false
	14	300	true	false	1	2	600	1	399		DO_NO 0		true
Other_Tracked_Alt	15	601	true	false	2	2	600	2	399		DO_NO T		false
• 1 + 0	16	299	true	false	1	1	601	3	399		DO_NO 0		true
	17	300	true	true	1	2	600	0	399	640	DO NO 0	DTHER	false
🖻 🧰 Own_Tracked_Alt_Rate	18	601	false	true	2	1	601	1	399	739	DO_NO T	CAS TA	true
• 600	19	299	false	true	1	2	600	2	399		NO INT C		false
• 601	20	300	false	false	2	1	601	3	399	840	NO INT T		
Alt_Layer_Value	21	601	true	false	2	1	601	1			DO_NO C	_	true
• • 0	22	299	false	true	1	2	600	0	400		NO_INT T		
• 1	23	300	*	*	*	*	*	3	400		DO_NO T		*
• 2	24	601	*	*	*	*	*	2	400		NO_INT *		*
L • 3	25	299	*	*	*	*	*	1			NO_INT *		*
🗐 📛 Up_Separation	26	300	*	*	*	*	*	0	400	639	DO_NO *		*
• • •	27	601	*	*	*	*	*	3			DO_NO *		*
• 399	28	299	*	*	*	*	*	2			DO_NO *		*
• 400	29	300	*	*	*	*	*	1		740	DO_NO *		*
• 499	30	601	*	*	*	*	*	0	400	840	DO_NO *		*
• • • 500	31	299	true	true	1	1	600	3		0	NO INT C		true
• 639	32	300	false	false	2	2	601	2	499	0 399	DO NO T		



Output options

Mappable values

Degree of interaction coverage: 2 Number of parameters: 12 Number of tests: 100

0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 1 1 1 1 1 1 1 1 0 1 1 1 1 2 0 1 0 1 0 2 0 2 2 1 0 0 1 0 1 0 1 3 0 3 1 0 1 1 1 0 0 0 1 0 1 0 4 2 1 0 2 1 0 1 1 0 1 0 5 0 0 1 0 1 1 1 0 1 0 3 0 7 0 1 1 2 0 1 1 0 1 0 1 0 8 1 0 0 1 0 0 0 1 0 1 0 1 0 9 2 1 1 1 1 0 0 1 0 2 1 0 1 0 1 Etc.

Human readable

Degree of interaction coverage: 2 Number of parameters: 12 Maximum number of values per parameter: 10 Number of configurations: 100

Configuration #1:

- 1 = Cur_Vertical_Sep=299
- 2 = High_Confidence=true
- 3 = Two_of_Three_Reports=true
- 4 = Own_Tracked_Alt=1
- 5 = Other_Tracked_Alt=1
- 6 = Own_Tracked_Alt_Rate=600
- 7 = Alt_Layer_Value=0
- 8 = Up_Separation=0
- 9 = Down_Separation=0
- 10 = Other_RAC=NO_INTENT
- 11 = Other_Capability=TCAS_CA
- 12 = Climb_Inhibit=true



Model checking example



```
-- specification for a portion of tcas - altitude separation.
-- The corresponding C code is originally from Siemens Corp. Research
-- Vadim Okun 02/2002
MODULE main
VAR
  Cur Vertical Sep : { 299, 300, 601 };
  High Confidence : boolean;
. . .
init(alt sep) := START ;
  next(alt sep) := case
    enabled & (intent_not_known | !tcas_equipped) : case
      need upward RA & need downward RA : UNRESOLVED;
      need upward RA : UPWARD RA;
      need downward RA : DOWNWARD RA;
      1 : UNRESOLVED;
    esac;
    1 : UNRESOLVED;
  esac;
. . .
SPEC AG ((enabled & (intent not known | !tcas equipped) &
!need downward RA & need upward RA) -> AX (alt sep = UPWARD RA))
-- "FOR ALL executions,
-- IF enabled & (intent not known ....
-- THEN in the next state alt sep = UPWARD RA"
```

Computation Tree Logic



The usual logic operators, plus temporal:

A ϕ - All: ϕ holds on all paths starting from the current state.

E ϕ - Exists: ϕ holds on some paths starting from the current state.

G ϕ - Globally: ϕ has to hold on the entire subsequent path.

F φ - Finally: φ eventually has to hold

X φ - Next: φ has to hold at the next state [others not listed]

```
execution paths
states on the execution paths
SPEC AG ((enabled & (intent_not_known |
!tcas_equipped) & !need_downward_RA & need_upward_RA)
-> AX (alt_sep = UPWARD_RA))
```

```
"FOR ALL executions,
IF enabled & (intent_not_known ....
THEN in the next state alt_sep = UPWARD_RA"
```

What is the most effective way to integrate combinatorial testing with model checking?

- Given AG(P -> AX(R))
 "for all paths, in every state, if P then in the next state, R holds"
- For k-way variable combinations, v1 & v2 & ... &
 vk
- vi abbreviates "var1 = val1"
- Now combine this constraint with assertion to produce counterexamples. Some possibilities:

1.AG(v1 & v2 & ... & vk & $P \rightarrow AX !(R)$)

2. AG(v1 & v2 & ... & vk \rightarrow AX !(1))

3. AG(v1 & v2 & ... & vk \rightarrow AX !(R))



What happens with these assertions?

1. AG(v1 & v2 & ... & vk & P \rightarrow AX !(R))

P may have a negation of one of the v_i , so we get

0 -> AX !(R))

always true, so no counterexample, no test. This is too restrictive!

1. AG(v1 & v2 & ... & vk \rightarrow AX !(1))

The model checker makes non-deterministic choices for variables not in v1..vk, so all R values may not be covered by a counterexample.

This is too loose!

2. AG(v1 & v2 & ... & vk -> AX !(R)) Forces production of a counterexample for each R. This is just right!



Modeling & Simulation

- 1. Aerospace Lockheed Martin analyze structural failures for aircraft design
- 2. Network defense/offense operations - NIST – analyze network configuration for vulnerability to deadlock



Example 3: Network Simulation

- "Simured" network simulator
 - Kernel of ~ 5,000 lines of C++ (not including GUI)
- Objective: detect configurations that can produce deadlock:
 - · Prevent connectivity loss when changing network
 - . Attacks that could lock up network
- Compare effectiveness of random vs. combinatorial inputs
- Deadlock combinations discovered
- Crashes in >6% of tests w/ valid values (Win32 version only)



Simulation Input Parameters

	Parameter	Values
1	DIMENSIONS	1,2,4,6,8
2	NODOSDIM	2,4,6
3	NUMVIRT	1,2,3,8
4	NUMVIRTINJ	1,2,3,8
5	NUMVIRTEJE	1,2,3,8
6	LONBUFFER	1,2,4,6
7	NUMDIR	1,2
8	FORWARDING	0,1
9	PHYSICAL	true, false
10	ROUTING	0,1,2,3
11	DELFIFO	1,2,4,6
12	DELCROSS	1,2,4,6
13	DELCHANNEL	1,2,4,6
14	DELSWITCH	1,2,4,6

5x3x4x4x4x4x2x2 x2x4x4x4x4x4 = 31,457,280 configurations

Are any of them dangerous?

If so, how many?

Which ones?



Network Deadlock Detection

Deadlocks Detected: combinatorial

			1000	2000	4000	8000
t	Tests	500 pkts	pkts	pkts	pkts	pkts
2	28	0	0	0	0	0
3	161	2	3	2	3	3
4	752	14	14	14	14	14

Average Deadlocks Detected: random

+	Tosts	500 pkts	1000 pkts	2000 pkts	4000 pkts	8000 pkts
L	TESIS	JUU pKtS	ρκιδ	pres	ρκισ	ρκισ
2	28	0.63	0.25	0.75	0.50	0.75
3	161	3	3	3	3	3
4	752	10.13	11.75	10.38	13	13.25





Network Deadlock Detection

Detected 14 configurations that can cause deadlock: $14/31,457,280 = 4.4 \times 10^{-7}$

Combinatorial testing found more deadlocks than random, including some that <u>might never have been</u> <u>found</u> with random testing

Why do this testing? Risks:

- accidental deadlock configuration: low
- deadlock config discovered by attacker: much higher (because they are looking for it)

Example 4: Buffer Overflows

Empirical data from the National Vulnerability Database

- Investigated > 3,000 denial-of-service vulnerabilities reported in the NIST NVD for period of 10/06 – 3/07
- Vulnerabilities triggered by:
 - Single variable 94.7% example: Heap-based buffer overflow in the SFTP protocol handler for Panic Transmit ... allows remote attackers to execute arbitrary code via a long ftps:// URL.
 - 2-way interaction 4.9% example: single character search string in conjunction with a single character replacement string, which causes an "off by one overflow"
 - 3-way interaction 0.4% example: Directory traversal vulnerability when register_globals is enabled and magic_quotes is disabled and .. (dot dot) in the page parameter



Finding Buffer Overflows

•••••



- 1. if (strcmp(conn[sid].dat->in_RequestMethod, "POST")==0) {
- 2. if (conn[sid].dat->in_ContentLength<MAX_POSTSIZE) {

3. conn[sid].PostData=calloc(conn[sid].dat->in_ContentLength+1024, sizeof(char));

	•••••
4.	pPostData=conn[sid].PostData;
5.	do {
6.	<pre>rc=recv(conn[sid].socket, pPostData, 1024, 0);</pre>
	•••••
7.	pPostData+=rc;
8.	x+=rc;
9.	<pre>} while ((rc==1024) (x<conn[sid].dat->in_ContentLength));</conn[sid].dat-></pre>
10.	conn[sid].PostData[conn[sid].dat->in_ContentLength]='\0';
11.	}



Interaction: request-method="POST", contentlength = -1000, data= a string > 24 bytes

- 1. if (strcmp(conn[sid].dat->in_RequestMethod, "POST")==0) {
- 2. if (conn[sid].dat->in_ContentLength<MAX_POSTSIZE) {

3. conn[sid].PostData=calloc(conn[sid].dat->in_ContentLength+1024, sizeof(char));

4.	pPostData=conn[sid].PostData;

.....

....

5. do {

6. rc=recv(conn[sid].socket, pPostData, 1024, 0);

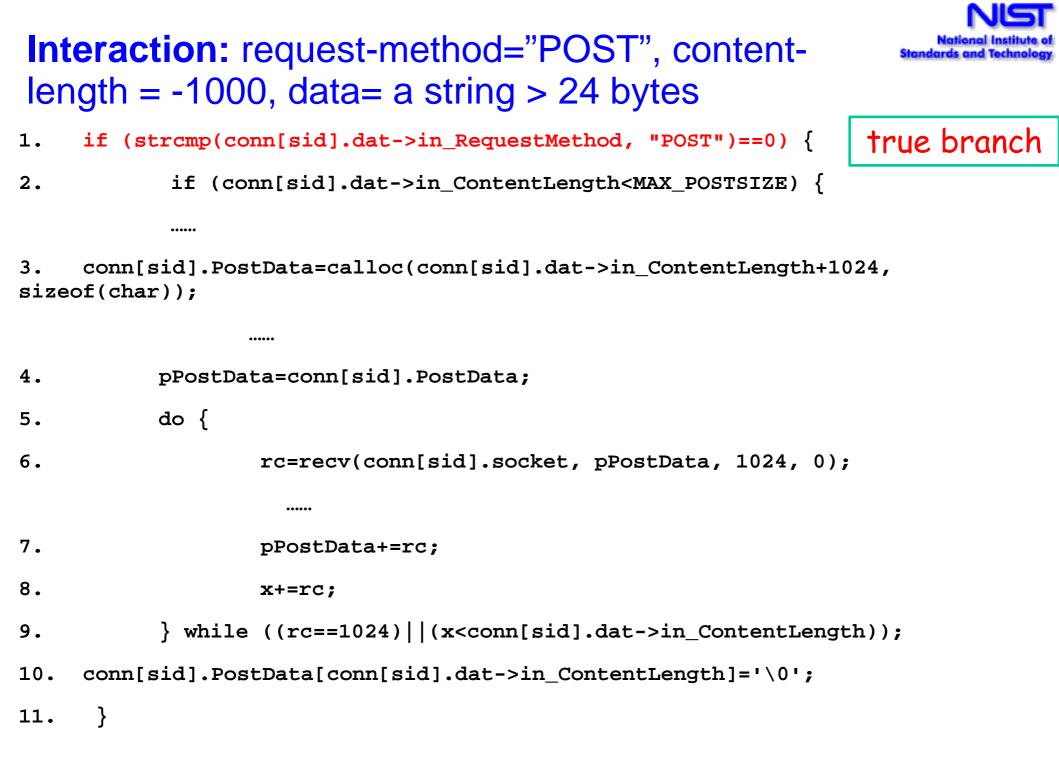
7. pPostData+=rc;

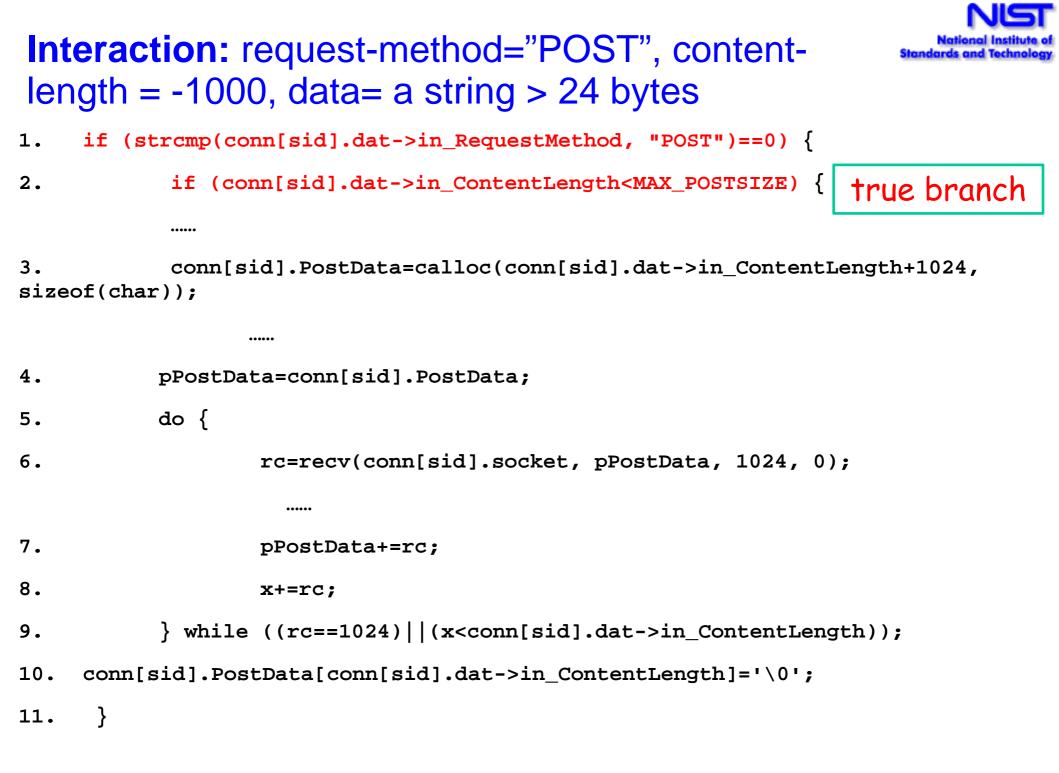
8. x+=rc;

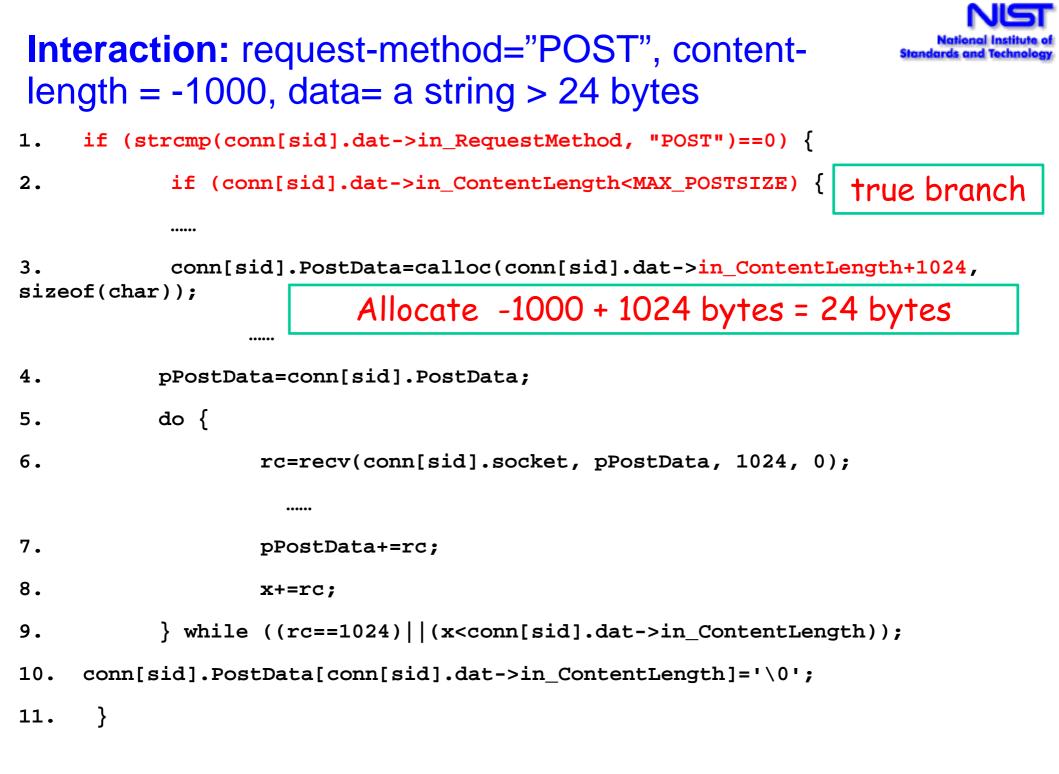
.....

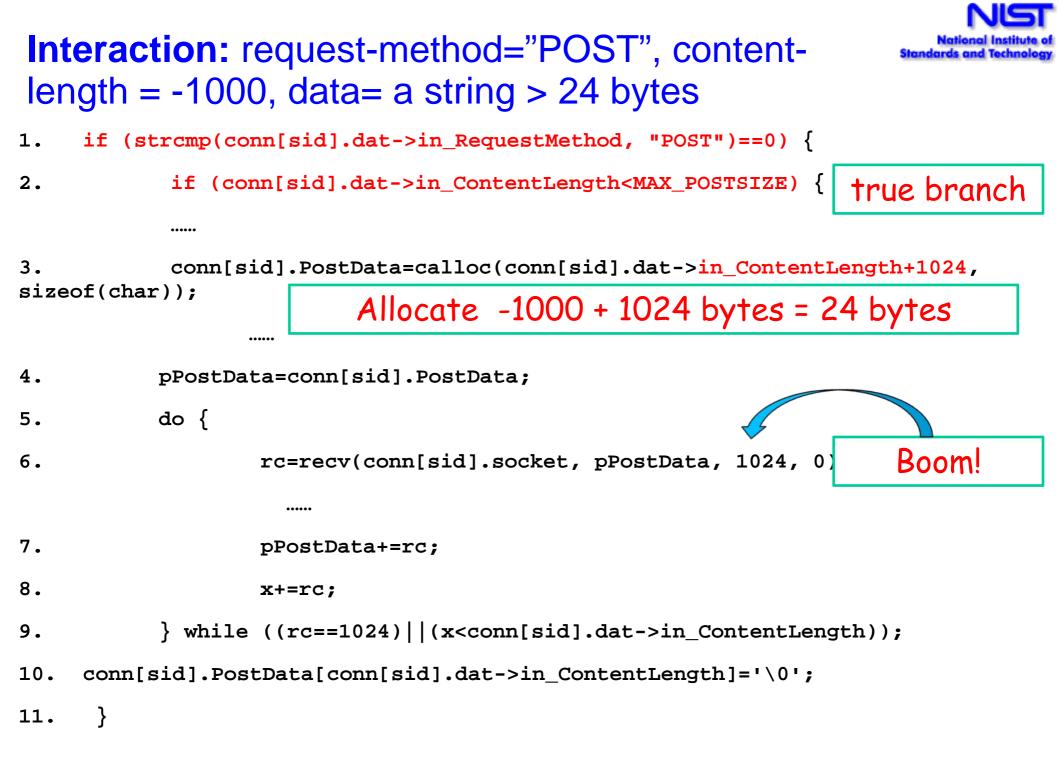
9. } while ((rc==1024)||(x<conn[sid].dat->in_ContentLength)); 10. conn[sid].PostData[conn[sid].dat->in_ContentLength]='\0';

11. }









Tutorial Overview



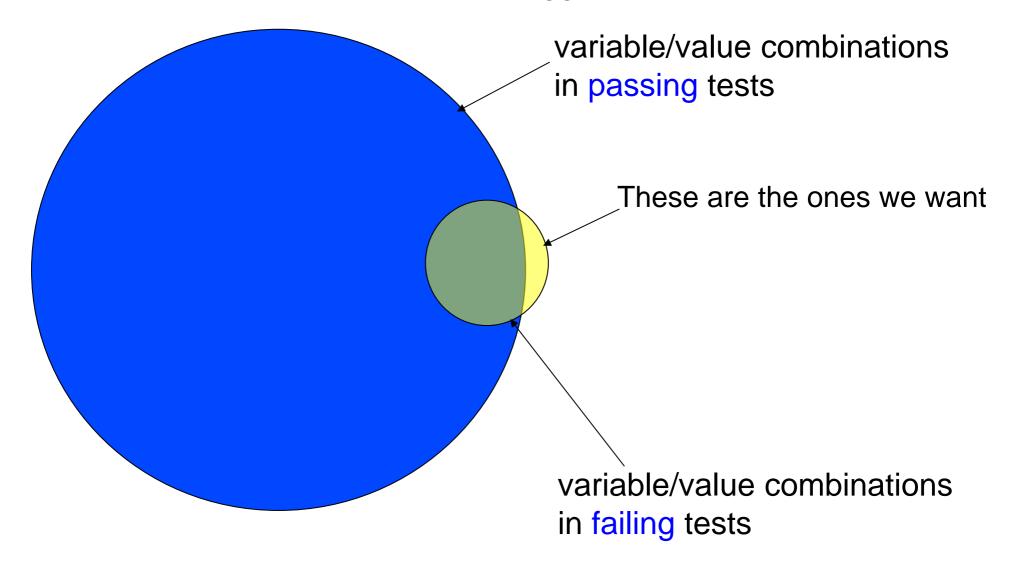
- 1. Why are we doing this?
- 2. What is combinatorial testing?
- 3. What tools are available?
- 4. Is this stuff really useful in the real world?

5.What's next?

Fault location



Given: a set of tests that the SUT fails, which combinations of variables/values triggered the failure?



Fault location – what's the problem?

If they're in failing set but not in passing set:

1. which ones triggered the failure?

2. which ones don't matter?

out of $v^t \binom{n}{t}$ combinations

Example:

- 30 variables, 5 values each
- = 445,331,250

5-way combinations

142,506 combinations in each test



Tutorial Overview



- 1. Why are we doing this?
- 2. What is combinatorial testing?
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Tutorial Overview

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- **Tutorial Overview**
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Tradeoffs

Advantages

- Tests rare conditions
- Produces high code coverage
- Finds faults faster
- May be lower overall testing cost
- Disadvantages
 - Expensive at higher strength interactions (>4-way)
 - May require high skill level in some cases (if formal models are being used)